11th European Symposium on Semiconductor Detectors



Contribution ID: 63 Type: not specified

Development of silicon double sided strip detectors for ion spectroscopy and tracking at EXL experiment of FAIR program at GSI

Monday, 8 June 2009 10:40 (1 minute)

Presenter: EREMIN, Vladimir (Ioffe Physico-Technical Institute of Russian Academy of Sciences)

Session Classification: Coffee Break and Poster Session I